

SIMTEK6349

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of
Chihiro Araki

App. No.: 10/063,869

Filed: May 21, 2002

Conf. No.: 2434


Title: INSPECTION METHOD AND
INSPECTION APPARATUS FOR
SEMICONDUCTOR CIRCUIT

Examiner: T. Nguyen

Art Unit: 2829

Commissioner for Patents
Arlington, VA 22313-1450I hereby certify that this correspondence and all
marked attachments are being deposited with
the United States Patent Office via fax to
(703) 872-9319 on:

September 11, 2003


Ernest A. Beutler
Reg. No. 19901PROPOSED AMENDMENT AFTER FINAL

Dear Sir:

In response to the Final Office Action, dated July 9, 2003, entry of the following amendment is requested, as placing this case in obvious condition for allowance or in better form for appeal:

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